



INFORMATION CITED BY APPLICANTS THAT MAY BE MATERIAL TO THE
PROSECUTION OF THE SUBJECT APPLICATION

Applicants: R.B. Darling et al. Attorney Docket No. UOFW116278
Application No.: 09/744,360 Group Art Unit: 2881
Filed: January 22, 2001 Examiner: --
Title: CHARGED PARTICLE BEAM DETECTION SYSTEM

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U.S. PATENT DOCUMENTS

*Examiner Initial	ID	Document No.	Date	Name
<u>A.Z.</u>	U1	4,290,012	09/15/1981	Berte et al.
<u>A.Z.</u>	U2	4,973,840	11/27/1990	Srivastava
<u>A.Z.</u>	U3	4,992,742	02/12/1991	Okuda et al.
<u>A.Z.</u>	U4	5,198,676	03/30/1993	Benveniste et al.

FOREIGN PATENT DOCUMENTS

*Examiner Initial	ID	Document No.	Date	Country	Translation Provided	
					Yes	No

NONE

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OTHER INFORMATION
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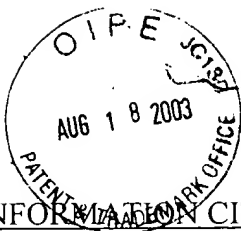
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12/19/03

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Applicants: R.B. Darling et al. Attorney Docket No. UWOTL116278
Application No.: 09/744,360 Group Art Unit: 3653
Filed: January 22, 2001 Examiner: T.N. Nguyen
Title: CHARGED PARTICLE BEAM DETECTION SYSTEM

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GROUP 3600

U.S. PATENT DOCUMENTS

*Examiner Cite	Kind	Date		
Initials No.	Document No.	Code	(mm/dd/yyyy)	Name
<u>A.2</u> U5	4,724,324		02/09/1988	Liebert

FOREIGN PATENT DOCUMENTS

*Examiner Cite	Kind	Publication Date	Country	English
Initial No.	Document No.	Code	(mm/dd/yyyy)	Abstract Translation
				Provided Provided

NONE

OTHER INFORMATION

(Including Author, Title, Date, Pertinent Pages, Etc.)

*Examiner Cite		
Initial No.		
<u>A.2</u> O1	Natsuaki, N., et al., "Spatial Dose Uniformity Monitor for Electrically Scanned Ion Beam," <i>Rev. Sci. Instrum.</i> 49(9):1300-1304, September 1978.	
<u>A.2</u> O2	O'Morain, C., et al., "Large-Diameter Plasma Profile Monitoring System Using Faraday Cup and Langmuir Probe Arrays," <i>Meas. Sci. Technol.</i> 4:1484-1488, December 1993.	
<u>A.2</u> O3	Scheidemann, A.A. et al., "Linear Dispersion Mass Spectrometer," <i>Proceedings of the 47th American Society for Mass Spectrometry Conference on Mass Spectrometry and Allied Topics</i> , Dallas, Texas, June 1999.	

Examiner

Date Considered

A.2

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